

**Search Notes**

Application/Control No.

10/500,427

Examiner

Mohamed Charioui

Applicant(s)/Patent under  
Reexamination

KANTAKE, SHUUSUKE

Art Unit

2857

**SEARCHED**

Class	Subclass	Date	Examiner
702	58, 69, 72, 79, 104, 117	9/14/2005	MC
702	118, 124	9/14/2005	MC
702	125, 126	9/14/2005	MC
702	189	9/14/2005	MC
714	718, 727	9/14/2005	MC
714	742, 743	9/14/2005	MC
324	617, 765	9/14/2005	MC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Hal Wachsmann	9/14/2005	MC
East: ("LSI" or "VLSI" or "IC" or semiconductor\$1) with tester\$1 with (time near interval)	9/15/2005	MC
East: ("LSI" or "VLSI" or "IC" or semiconductor\$1) with tester\$1 with (time near interval) and jitter\$1	9/15/2005	MC
East: ("LSI" or "VLSI" or "IC" or semiconductor\$1) with tester\$1 with (time near interval) and (phase near difference)	9/15/2005	MC